


APPLICATION DATA SHEET

Electronic Version v14

Stylesheet Version v14.0

Title of Invention	METHOD FOR ANALYZING DEFECT INSPECTION PARAMETERS		
Application Type : regular, utility Attorney Docket Number : LKSP0018USA			
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Priority Data: Doc.No: 091138167; Country -TW ; Date: 2002-12-31 us-priority-claimed			
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as our attorney(s) or agent(s) to prosecute the application identified above, and to transact all business in the United States Patent and Trademark Office connected therewith.